

### ACPL-P480 and ACPL-W480

## High CMR Intelligent Power Module and Gate Drive Interface Optocoupler

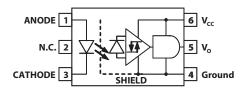
#### **Description**

The Broadcom<sup>®</sup> high-speed ACPL-P480/W480 optocoupler contains a GaAsP LED, a photo detector, and a Schmitt trigger that eliminates the requirement for external waveform conditioning circuits. The totem pole output eliminates the need for a pull-up resistor and allows for a direct-drive Intelligent Power Module or gate drive. Propagation delay difference between devices has been minimized to maximize inverter efficiency through reduced switching dead time.

## **Applications**

- IPM interface isolation
- Isolated IGBT/MOSFET gate drive
- AC and brushless DC motor drives
- Industrial inverters
- General digital isolation

## **Functional Diagram**



**NOTE:** A 0.1- $\mu$ F bypass capacitor must be connected between pins 4 and 6.

### **Truth Table (Non-Inverting Logic)**

LED	v <sub>o</sub>
ON	HIGH
OFF	LOW

#### **Features**

- Performance specified for common IPM applications over industrial temperature range
- Short maximum propagation delays
- Minimized pulse width distortion (PWD)
- Very high common mode rejection (CMR)
- Hysteresis
- Totem pole output (no pull-up resistor required)
- Available in stretched SO-6 package
- Package clearance/creepage at 8 mm (ACPL-W480)
- Safety approvals:
  - UL recognized with 3750V<sub>rms</sub> for 1 minute (5000V<sub>rms</sub> for 1 minute for all ACPL-W480 devices and Option 020 device for ACPL-P480) per UL1577
  - CSA approved
  - IEC/EN/DIN EN 60747-5-5 approved with  $\rm V_{IORM}$  =  $891\rm V_{peak}$  for ACPL-P480 and  $\rm V_{IORM}$  =  $1140\rm V_{peak}$  for ACPL-W480

### **Specifications**

- Wide operating temperature range: –40°C to 100°C
- Maximum propagation delay t<sub>PHL</sub>/t<sub>PLH</sub> = 350 ns
- Maximum pulse width distortion (PWD) = 250 ns
- Propagation delay difference: minimum –100 ns, maximum – 250 ns
- Wide operating V<sub>CC</sub> range: 4.5V to 20V
- 20 kV/µs minimum common mode rejection (CMR) at V<sub>CM</sub> = 1000V

**CAUTION!** It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.

## **Ordering Information**

ACPL-P480 is UL Recognized with  $3750V_{rms}$  for 1 minute and ACPL-W480 is UL Recognized with  $5000V_{rms}$  for 1 minute per UL1577. Both are approved under CSA Component Acceptance Notice #5, File CA 88324.

	Option				IEC/EN/DIN EN	
Part Number	RoHS Compliant	Package	Surface Mount	Tape and Reel	60747-5-5	Quantity
ACPL-P480	-000E	7 mm Stretched	X			100 per tube
	-500E	SO-6	X	Х		1000 per reel
	-020E		X			100 per tube
	-520E		X	Х		1000 per reel
	-060E		X		Х	100 per tube
	-560E		X	Х	X	1000 per reel
ACPL-W480	-000E	8 mm Stretched	Х			100 per tube
	-500E	SO-6	X	Х		1000 per reel
	-060E		X		Х	100 per tube
	-560E		X	Х	Х	1000 per reel

To order, choose a part number from the part number column and combine with the desired option from the option column to form an ordering part number.

#### Example 1:

ACPL-P480-560E to order product of Stretched SO-6 package in Tape and Reel packaging with IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

#### Example 2:

ACPL-P480-000E to order product of Stretched SO-6 package in tube packaging and RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information.

### Solder Reflow Profile

The recommended reflow profile is per JEDEC Standard, J-STD-020 (latest revision). Non-halide flux should be used.

## **Regulatory Information**

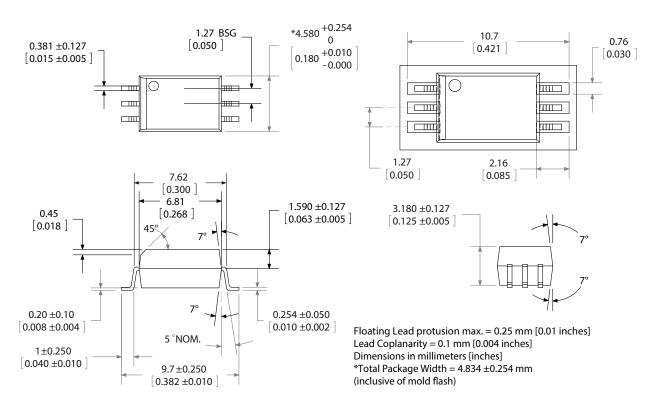
The ACPL-P480 and ACPL-W480 are approved by the following organizations:

- IEC/EN/DIN EN 60747-5-5 (Option 060 only):
  - IEC 60747-5-5: 2007
  - EN 60747-5-5: 2011
  - DIN EN 60747-5-5 (VDE 0884-5): 2011-11
- UL:
  - ACPL-P480: Approval under UL 1577, component recognition program up to  $V_{ISO}$  = 3750 $V_{rms}$ . File E55361.
  - ACPL-W480 and ACPL-P480 (option 020): Approval under UL 1577, component recognition program up to V<sub>ISO</sub> = 5000V<sub>rms</sub>. File E55361.
- CSA: Approval under CSA Component Acceptance Notice #5, File CA 88324.

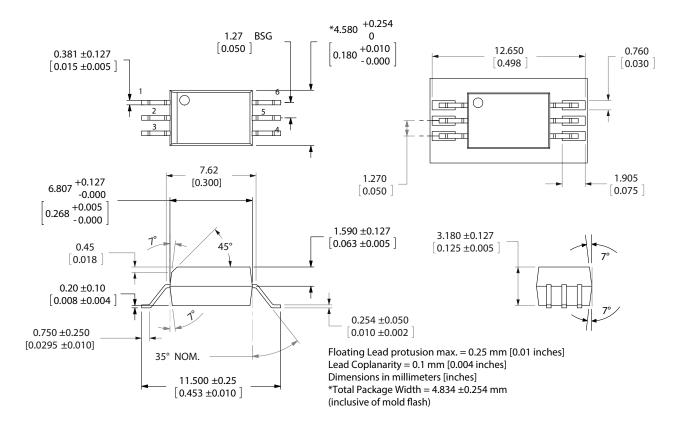
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## **Package Outline Drawings**

## ACPL-P480 Stretched SO-6 Package (7 mm Clearance)



## ACPL-W480 Stretched SO-6 Package (8 mm Clearance)



# IEC/EN/DIN EN 60747-5-5 Insulation Characteristics (Option 060)

Description	Symbol	ACPL-P480	ACPL-W480	Units
Installation Classification per DIN VDE 0110/39, Table 1				
For rated mains voltage ≤ 150V <sub>rms</sub>		I– IV	I – IV	
For rated mains voltage ≤ 300V <sub>rms</sub>		I – IV	I – IV	
For rated mains voltage ≤ 600V <sub>rms</sub>		I – III	I – IV	
Climatic Classification		55/10	0/21	
Pollution Degree (DIN VDE 0110/39)		2		
Maximum Working Insulation Voltage	V <sub>IORM</sub>	891	1140	V <sub>peak</sub>
Input to Output Test Voltage, Method b <sup>a</sup> V <sub>IORM</sub> x 1.875 = V <sub>PR</sub> , 100% Production Test with t <sub>m</sub> = 1 sec, Partial Discharge < 5 pC	V <sub>PR</sub>	1670	2137	V <sub>peak</sub>
Input to Output Test Voltage, Method a <sup>a</sup> V <sub>IORM</sub> x 1.6=V <sub>PR</sub> , Type and Sample Test, t <sub>m</sub> = 10s,  Partial Discharge < 5 pC	V <sub>PR</sub>	1426	1824	$V_{peak}$
Highest Allowable Overvoltage (Transient Overvoltage t <sub>ini</sub> = 60s)	V <sub>IOTM</sub>	6000	8000	$V_{peak}$
Safety-limiting Values – maximum values allowed in the	event of a failure	•	•	
Case Temperature	T <sub>S</sub>	17	75	°C
Input Current	I <sub>S, INPUT</sub>	23	30	mA
Output Power	P <sub>S, OUTPUT</sub>	600 m¹		mW
Insulation Resistance at T <sub>S</sub> , V <sub>IO</sub> = 500V	R <sub>S</sub>	>109		Ω

a. Refer to the optocoupler section of the Isolation and Control Components Designer's Catalog, under the Product Safety Regulations section, (IEC/EN/DIN EN 60747-5-5), for a detailed description of Method a and Method b partial discharge test profiles.

## **Insulation and Safety Related Specifications**

Parameter	Symbol	ACPL-P480	ACPL-W480	Unit	Condition
Minimum External Air Gap (External Clearance)	L(101)	7.0	8.0	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (External Creepage)	L(102)	8.0	8.0	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		0.08		mm	Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector.
Minimum Internal Tracking (Internal Creepage)		1	N/A		Measured from input terminals to output terminals, along internal cavity.
Tracking Resistance (Comparative Tracking Index)	CTI	>175		V	DIN IEC 112/VDE 0303 Part 1.
Isolation Group		1	IIIa		Material Group (DIN VDE 0110, 1/89, Table 1).

# **UL 1577 Specification Sheet**

		Curre	nt, mA	Powe	r, mW	Isolation	Maximum	Maximum	Maximum
Model	Package Type	Emitter	Sensor	Emitter	Sensor	Voltage 1 min, V <sub>rms</sub>	Operating Temperature, °C	Junction Temperature, °C	Storage Temperature, °C
P480	3	10	25	15	560	5000	110	125	125

# **Absolute Maximum Ratings**

Parameter	Symbol	Min.	Max.	Units
Storage Temperature	T <sub>S</sub>	<b>–</b> 55	+125	°C
Operating Temperature	T <sub>A</sub>	-40	+100	°C
Average Input Current	I <sub>F(AVG)</sub>	_	10	mA
Peak Transient Input Current (<1 µs pulse width, 300 pps) (<200 µs pulse width, <1% duty cycle)	I <sub>F(TRAN)</sub>		1.0 40	A mA
Reverse Input Voltage	V <sub>R</sub>	_	5	V
Average Output Current	Io	_	25	mA
Supply Voltage	V <sub>CC</sub>	0	25	V
Output Voltage	Vo	-0.5	+25	V
Total Package Power Dissipation <sup>a</sup>	P <sub>T</sub>	_	210	mW

a. Derate total package power dissipation, PT, linearly above 70°C free-air temperature at a rate of 4.5 mW/°C.

# **Recommended Operating Conditions**

Parameter	Symbol	Min.	Max.	Units	Note
Power Supply Voltage	V <sub>CC</sub>	4.5	20	V	
Forward Input Current (ON)	I <sub>F(ON)</sub>	6	10	mA	
Forward Input Voltage (OFF)	V <sub>F(OFF)</sub>	_	0.8	V	
Operating Temperature	T <sub>A</sub>	-40	+100	°C	

## **Electrical Specifications**

Over recommended operating conditions  $T_A = -40^{\circ}\text{C}$  to  $+100^{\circ}\text{C}$ ,  $V_{CC} = +4.5\text{V}$  to 20V,  $I_{F(ON)} = 6$  mA to 10 mA,  $V_{F(OFF)} = 0\text{V}$  to 0.8V, unless otherwise specified. All typicals at  $T_A = 25^{\circ}\text{C}$ .

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure	Note
Logic Low Output Voltage	V <sub>OL</sub>	_	_	0.5	V	I <sub>OL</sub> = 6.4 mA	1, 3, 9, 10	
Logic High Output Voltage	V <sub>OH</sub>	2.4	V <sub>CC</sub> -		V	I <sub>OH</sub> = -2.6 mA	2, 3, 7, 9,	
ACPL-P480		2.7	1.1			I <sub>OH</sub> = -0.4 mA	10	
ACPL-W480		2.7				I <sub>OH</sub> = -1.6 mA		
Threshold Input Current Low to High		_	2.2	5.5	mA			
Output Leakage Current	I <sub>OHH</sub>	_	_	100	μA	V <sub>CC</sub> = 5V, I <sub>F</sub> = 10 mA		
$(V_O = V_{CC} + 0.5V)$		_	_	500	μA	$V_{CC}$ = 20V, $I_F$ = 10 mA		
Logic Low Supply Current	I <sub>CCL</sub>	_	1.9	3.0	mA	$V_{CC} = 5.5V, V_F = 0V, I_O = Open$		
		_	2.0	3.0	mA	$V_{CC}$ = 20V, $V_F$ = 0V, $I_O$ = Open		
Logic High Supply Current	Іссн	_	1.5	2.5	mA	V <sub>CC</sub> = 5.5V, I <sub>F</sub> = 10 mA, I <sub>O</sub> = Open		
		_	1.6	2.5	mA	$V_{CC}$ = 20V, $I_F$ = 10 mA, $I_O$ = Open		
Logic Low Short Circuit	I <sub>OSL</sub>	25	_	_	mA	$V_{O} = V_{CC} = 5.5V, V_{F} = 0V$		а
Output Current		50	_	_	mA	$V_{O} = V_{CC} = 20V, V_{F} = 0V$		
Logic High Short Circuit Output Current	I <sub>OSH</sub>	_	_	<b>–25</b>	mA	$V_{CC} = 5.5V, I_F = 10 \text{ mA},$ $I_O = \text{Open}$		а
		_	_	<b>–</b> 50	mA	V <sub>CC</sub> = 20V, I <sub>F</sub> = 10 mA, I <sub>O</sub> = Open		
Input Forward Voltage	$V_{F}$	_	1.5	1.7	V	$T_A = 25^{\circ}C, I_F = 6 \text{ mA}$	4	
		_	_	1.85	V	I <sub>F</sub> = 6 mA		
Input Reverse Breakdown Voltage	$BV_R$	5	_	_	V	Ι <sub>R</sub> = 10 μΑ		
Input Diode Temperature Coefficient	$\Delta V_F / \Delta T_A$	_	1.7	_	mV/°C	I <sub>F</sub> = 6 mA		
Input Capacitance	C <sub>IN</sub>	_	60	_	pF	f = 1 MHz, V <sub>F</sub> = 0V		b

a. Duration of output short circuit time should not exceed 10 ms.

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b. Input capacitance is measured between pin 1 and pin 3.

## **Switching Specifications**

Over recommended operating conditions  $T_A = -40^{\circ}\text{C}$  to +100°C,  $V_{CC} = +4.5\text{V}$  to 20V,  $I_{F(ON)} = 6$  mA to 10 mA,  $V_{F(OFF)} = 0\text{V}$  to 0.8V, unless otherwise specified. All typicals at  $T_A = 25^{\circ}\text{C}$ .

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure	Note
Propagation Delay Time to Logic Low Output Level	t <sub>PHL</sub>	_	150	350	ns	with Peaking Capacitor	5, 6	а
Propagation Delay Time to Logic High Output Level	t <sub>PLH</sub>	_	110	350	ns	with Peaking Capacitor	5, 6	а
Pulse Width Distortion	$ t_{PHL} - t_{PLH}  = PWD$	_	_	250	ns			b
Propagation Delay Difference Between Any Two Parts	PDD	-100	_	+250	ns			С
Output Rise Time (10% to 90%)	t <sub>r</sub>	_	16	_	ns		5, 8	
Output Fall Time (90% to 10%)	t <sub>f</sub>	_	20	_	ns		5, 8	
Logic High Common Mode Transient Immunity	CM <sub>H</sub>	20	_	_	-	$ V_{CM}  = 1000V, I_F = 6.0 \text{ mA}$ $V_{CC} = 5V, T_A = 25^{\circ}C$	11	d
Logic Low Common Mode Transient Immunity	CM <sub>L</sub>	20	_	_	kV/μs	$ V_{CM}  = 1000V, V_F = 0V,$ $V_{CC} = 5V, T_A = 25^{\circ}C$	11	d

- a. The t<sub>PLH</sub> propagation delay is measured from the 50% point on the leading edge of the input pulse to the 1.3V point on the leading edge of the output pulse. The t<sub>PHL</sub> propagation delay is measured from the 50% point on the trailing edge of the input pulse to the 1.3V point on the trailing edge of the output pulse.
- b. Pulse Width Distortion (PWD) is defined as  $|t_{\text{PHL}} t_{\text{PLH}}\,|$  for any given device.
- c. The difference between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  between any two devices under the same test condition.
- d.  $CM_H$  is the maximum slew rate of the common mode voltage that can be sustained with the output voltage in the logic high state,  $V_O > 2.0V$ .  $CM_L$  is the maximum slew rate of the common mode voltage that can be sustained with the output voltage in the logic low state,  $V_O < 0.8V$ .

## **Package Characteristics**

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Figure	Note
Input-Output Momentary Withstand Voltage <sup>a</sup>	V <sub>ISO</sub>	3750 <sup>b</sup> 5000 <sup>c</sup>			V <sub>rms</sub>	RH < 50%, t = 1 min. T <sub>A</sub> = 25°C		d, e
Input-Output Resistance	$R_{I-O}$		10 <sup>12</sup>			$V_{I-O} = 500V_{DC}$		d
Input-Output Capacitance	C <sub>I-O</sub>		0.6			f = 1 MHz, V <sub>I-O</sub> = 0V <sub>DC</sub>		d, f

- a. The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating. For the continuous voltage rating refer to the IEC/EN/DIN EN 60747-5-5 Insulation Characteristics Table (if applicable).
- b. For all ACPL-P480 devices except Option 020.
- c. For ACPL-W480 and Option 020 of ACPL-P480).
- d. The device is considered a two-terminal device: pins 1, 2, and 3 shorted together and pins 4, 5, and 6 shorted together.
- e. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage 4500V<sub>rms</sub> for one second (leakage detection current limit, I<sub>LO</sub> ≤ 5 μA); each optocoupler with option 020 is proof tested by applying an insulation test voltage. 6000V<sub>rms</sub> for 1 second (leakage detection current limit, I<sub>LO</sub> ≤ 5 μA). This test is performed before the 100% production test for partial discharge (Method b) shown in the IEC/EN/DIN EN 60747-5-2 Insulation Characteristics Table, if applicable.
- f. Use of a 0.1  $\mu$ F bypass capacitor connected between pins 4 and 6 is recommended.

Figure 1: Typical Logic Low Output Voltage vs. Temperature

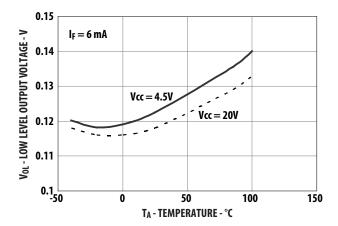


Figure 2: Typical Logic High Output Current vs. Temperature

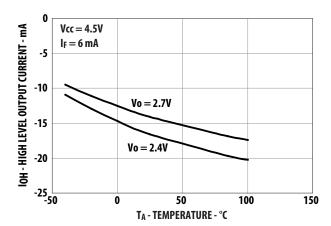


Figure 3: Typical Output Voltage vs. Forward Input Current

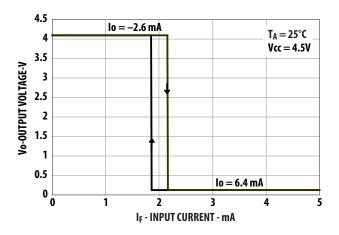


Figure 4: Typical Input Diode Forward Characteristic

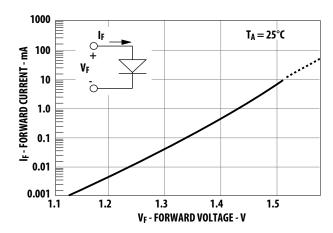
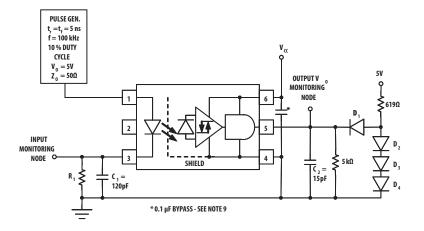


Figure 5: Test Circuit for t<sub>PLH</sub>, t<sub>PHL</sub>, t<sub>r</sub>, and t<sub>f</sub>



THE PROBE AND JIG CAPACITANCES ARE INCLUDED IN  $\mathbf{C_1}$  AND  $\mathbf{C_2}$ .

R <sub>1</sub>	580Ω	330Ω
I <sub>F(ON)</sub>	6 mA	10 mA

ALL DIODES ARE 1N916 OR 1N3064.

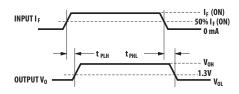


Figure 6: Typical Propagation Delays vs. Temperature

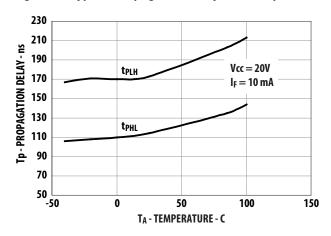


Figure 8: Typical Propagation Delay vs. Supply Voltage

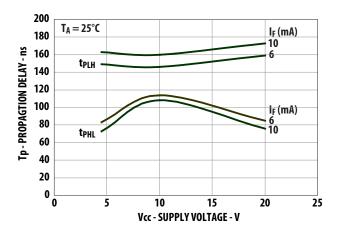


Figure 10:  $V_{OL}$  vs.  $I_{OL}$  Across Temperatures

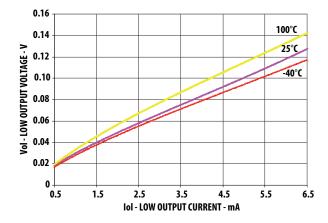


Figure 7: Typical Logic High Output Voltage vs. Supply Voltage

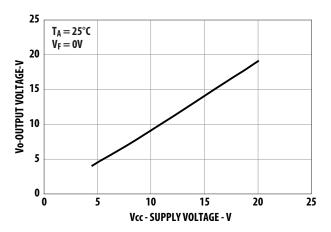


Figure 9:  $V_{OH}$  vs.  $I_{OH}$  Across Temperatures

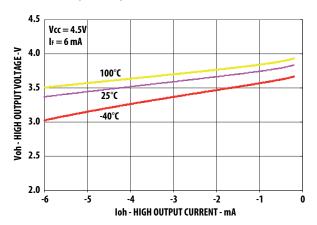
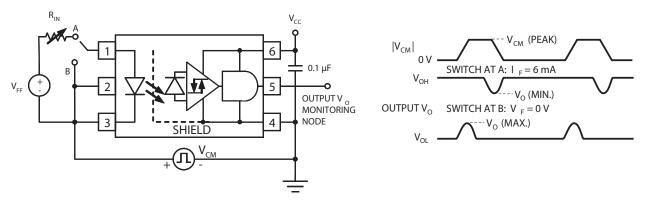


Figure 11: Test Circuit for Common Mode Transient Immunity and Typical Waveforms



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